

Application/Control No.	Applicant(s)/Patent under Reexamination MIYAWAKI ET AL.	
10/516,314		
Examiner	Art Unit	
Jae W. Lee, Ph.D.	1656	

SEARCHED				
Class	Subclass	Date	Examiner	
NONE	NONE	6/27/2007	JWL	
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
STN databases: BIOSIS, CAPLUS, EMBASE, MEDLINE, SCISEARCH, AND JAPIO, see attached search history printouts	6/27/2007	JWL		
EAST inventor name search	6/27/2007	JWL		
PALM inventor name search	6/27/2007	JWL		